# 8251/Am9551

Programmable Communication Interface iAPX86 Family
MILITARY INFORMATION

# DISTINCTIVE CHARACTERISTICS

- Separate control and transmit register input buffers
- Synchronous or asynchronous serial data transfer
- Parity, overrun, and framing errors detected
- Half- or full-duplex signaling
- Character length of 5, 6, 7, or 8 bits
- Internal or external synchronization
- Odd parity, even parity, or no parity bit
- Modem interface controlled by processor
  - Programmable Sync pattern
  - Fully TTL-compatible togic levels

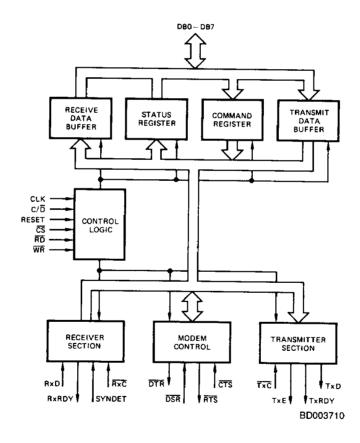
# **GENERAL DESCRIPTION**

The 8251/Am9551 is a programmable serial data communication interface that provides a Universal Synchronous/Asynchronous Receiver/Transmitter (USART) function. It is normally used as a peripheral device for an associated processor and may be programmed by the processor to operate in a variety of standard serial communication formats.

The device accepts parallel data from the CPU, formats and serializes the information based on its current operating mode, and then transmits the data as a serial bit stream. Simultaneously, serial data can be received, converted into parallel form, deformatted, and then presented to the CPU. The USART can operate in an independent full-duplex mode.

Data, control, operation, and format options are all selected by commands from an associated processor. This provides an unusual degree of flexibility and allows the 8251/ Am9551 to service a wide range of communication disciplines and applications.

### **BLOCK DIAGRAM**

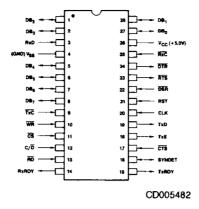


Publication # Rev. Amendment
09233 A /0
Issue Date: November 1987

3-33

# CONNECTION DIAGRAM Top View

**DIPs** 



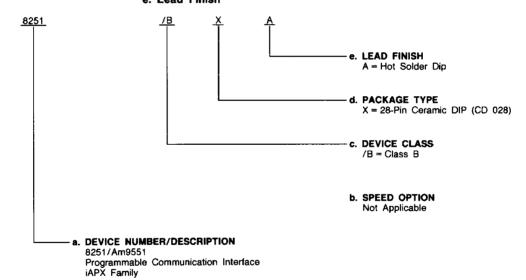
Note: Pin 1 is marked for orientation.

# **MILITARY ORDERING INFORMATION**

# **APL Products**

AMD products for Aerospace and Defense applications are available in several packages and operating ranges. APL (Approved Products List) products are fully compliant with MIL-STD-883C requirements. The order number (Valid Combination) for APL products is formed by a combination of: **a. Device Number** 

- b. Speed Option (if applicable)
- c. Device Class
- d. Package Type
- e. Lead Finish



# Valid Combinations 8251 AM9551 /BXA

#### **Valid Combinations**

Valid Combinations list configurations planned to be supported in volume for this device. Consult the local AMD sales office to confirm availability of specific valid combinations or to check for newly released valid combinations.

# **Group A Tests**

Group A tests consist of Subgroups 1, 2, 3, 7, 8, 9, 10, 11.

# **ABSOLUTE MAXIMUM RATINGS**

Storage Temperature	65°C	to	+ 150	°C
V <sub>CC</sub> with Respect to V <sub>SS</sub>	~0.5	to	+7.0	٧
All Signal Voltages				
with Respect to VSS	0.5 V	to	+7.0	٧
Power Dissipation	• • • • • • • • • • • • • • • • • • • •		1.0	W

Stresses above those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent device failure. Functionality at or above these limits is not implied. Exposure to absolute maximum ratings for extended periods may affect device reliability.

# **OPERATING RANGES**

Military (M) Devices	
Temperature (T <sub>C</sub> )55 to +125°C	>
Supply Voltage (VCC) 5 V ± 10%	•

Operating ranges define those limits between which the functionality of the device is guaranteed.

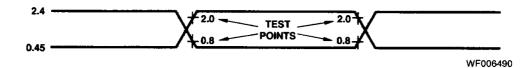
DC CHARACTERISTICS over operating range (for APL Products, Group A, Subgroups 1, 2, 3 are tested unless otherwise noted)

Parameter Symbol	Parameter Description	Test Conditions	8251		Am9551			
			Min.	Max.	Min.	Max.	Unit	
VOH	Output HIGH Voltage	$I_{OH} = -200 \mu A$ , $V_{CC} = 4.5 V$		100	2.4			
	- Culput their tonage	$I_{OH} = -100 \mu A$	. 24	1 3 4			<b>┤</b>	
VOL	Output LOW Voltage	I <sub>OL</sub> = 1.6 mA, V <sub>CC</sub> = 4.5 V		45		0.45	V	
V <sub>IH</sub>	Input HIGH Voltage	V <sub>CC</sub> = 5 V ± 109	2.2	V <sub>CC</sub> *	2.2	Vcc*	v	
VIL	Input LOW Voltage	Vcc 5 V 10%	-0.5*	0.8	-0.5*	0.8	V	
ILI	Input Load Current	V <sub>C</sub> = 5.5 = 5 V 0 V	†	±10		±10	μА	
Data Bus Linkath	Data Bus I was	$V_{OU} = 0.5 V, V_{CC} = 5.5 V$		-50	<del>                                     </del>	-50	μ.,	
		OUT = 5.5 V, V <sub>CC</sub> = 5.5 V		10		10	μΑ	
loc	V <sub>CC</sub> Supply Correct			120		120	mA	
Co t	Output Capacitance			15*		15*	pF	
C <sub>I</sub> †	Input Capacitance	7		10*		10*	pF	
C1/0 †	I/O Capacitance fc = 1.0 MHz, Inputs = 0 V			20*		20*	pF	

<sup>\*</sup> Guaranteed by design; not tested. † Not included in Group A tests.

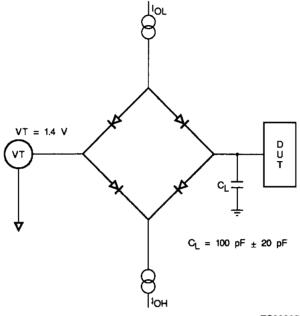
Notes: 1. ICC is measured in a static condition with outputs in the worst-case condition with all outputs unloaded.

# SWITCHING TEST INPUT/OUTPUT WAVEFORM



AC testing inputs are driven at 2.4 V for a logic "1" and 0.45 V for a logic "0." Timing measurements are made at 2.0 V for a logic "1" and 0.8 V for a logic "0."

# **SWITCHING TEST CIRCUIT**



TC003851

This test circuit is the dynamic load of a Teradyne J941.

SWITCHING CHARACTERISTICS over operating range (for APL Products, Group A, Subgroups 9, 10, 11 are tested unless otherwise noted) (Note 4)

Parameter	Parameter Description		8:	8251		Am9551	
Symbol			Min.	Max.	Min.	Max.	Unit
t <sub>AR</sub>	CS, C/D Stable to READ LOW Setup Time			<del>                                     </del>	50	<del> </del>	ns
t <sub>AW</sub>	CS, C/D Stable to WRITE LOW Setup Tir	ne	20	-	20	<del>                                     </del>	ns
t <sub>CR</sub>	DSR, CTS to READ LOW Setup Time			16		16	tcy
t <sub>CY</sub>	Clock Period		0.420	1.35	0.380	1.35	μs
t <sub>DF</sub>	READ HIGH to Data Bus Off Delay		25	200	25	200	ns
t <sub>DTx</sub>	TxC LOW to TxD Delay			1.0		1.0	μs
t <sub>DW</sub>	Data to WRITE HIGH Setup Time		200		150	1.0	ns
t <sub>ES</sub>	External SYNDET to RxC LOW Setup Time	9	16		16	<del>                                     </del>	tcy
t <sub>HRx</sub>	Sampling Pulse to Rx Data Hold Time (No	te 5)	2.0		2.0		μs
t <sub>IS</sub>	Data Bit (Center) to Internal SYNDET Dela	у		30		30	
tφW	Clock Pulse Width	·	220	0.6t <sub>CY</sub>	175	0.6t <sub>CY</sub>	t <sub>CY</sub>
t <sub>RA</sub>	READ HIGH to CS, C/D Hold Time		5.0	0.0407	5.0	U.UICY	<del></del>
t <sub>RD</sub>	READ LOW to Data Bus On Delay			350	3.0	250	ns
		1x Baud Rate		330	15	250	ns
<sup>t</sup> RPD	Receiver Clock HIGH Time	16x & 64x			<u> </u>	<del> </del>	tcy
		Baud Rate	3		3		0.
<b>t</b>	Receiver Clock LOW Time	1x Baud Rate	12	-	12		tcy
tRPW		16x & 64x Baud Rate	1		1		
t <sub>RR</sub>	READ Pulse Width				380		ns
t <sub>RV</sub>	Time Between WRITE Pulses During Initialization (Note 1)				6.0		tcy
t <sub>Rx</sub>	Data Bit (Center) to RxRDY Delay			20		20	tov
tSRx	Rx Data to Sampling Pulse Setup Time (No		2.0		2.0	20	t <sub>CY</sub> μS
t <sub>TPD</sub>		Baud Rate	15		15		t <sub>CY</sub>
	Transmitter Clock HIGH Time	16x & 64x				<u> </u>	
		Baud Rate	3		3		
tTPW	Transmitter Clock LOW Time	1x Baud Rate	12		12		
· IPW	Transmitter Clock LOW Time	16x & 64x Baud Rate	1		1		tCY
tTX	Data Bit (Center) Jx D. Delay			16		16	tcy
t <sub>TxE</sub>	Data Bit (Center) to CX MPTY Delay			16		16	tcy
twa	WRITE HIGH to CS, C/D Hold Time		20		20		ns
twc	WRITE HIGH to TxE, DTR, RTS Delay			16		16	tcy
two	WRITE HIGH to Data Hold Time		40		40		ns
tww	WRITE Pulse Width		430		380		ns
	D	1x Baud Rate	DC	56	DC	56	kHz
f <sub>Rx</sub>	Receiver Clock Frequency	16x & 64x Baud Rate	DC	520	DC	520	
		1x Baud Rate	DC	56	DC	56	
f⊤x	Transmitter Clock Frequency	16x & 64x	DC	520	DC		kHz

Notes: 1. This time period between write pulses is specified for initialization purposes only when MODE, SYNC 1, SYNC 2, COMMAND, and first DATA BYTE are written into the Am9551. Subsequent writing of both COMMAND and DATA are only allowed when TxRDY = 1. t<sub>RV</sub> after internal Reset = 8 \* t<sub>CV</sub>.

2. Reset Pulse Width = 6t<sub>CV</sub> Min.
3. Switching Characteristics parameters are listed in alphabetical order.
4. Clock Rise and Fall times are controlled by the Teradyne J941 tester. Measurement of typical signals generated by the J941 showed to = tc = 5 ns

th = tr = 5 ns.

5. Sampling pulse is internal and not tested; guaranteed by design.